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STATEMENT BY APPLICANT**

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Complete if Known

Application Number	10/532,390
Filing Date	Oct/24/2003
First Named Inventor	Haj-Yehia
Art Unit	6614
Examiner Name	N/A
Attorney Docket Number	0-06-225

Sheet 3 of 7**U. S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
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